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In re Applicant:

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TECHNOLOGY CEN..

DU-NOUR

§

Serial No.: 09/762,473

§

Filed: 7 FEB 2001

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Group Art Unit: 2877

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For: METHOD AND APPARATUS FOR
MEASURING THE THICKNESS OF
A FILM PARTICULARLY OF A
PHOTORESIST FILM ON A
SEMICONDUCTOR SUBSTRATE

§

Attorney Docket No.: 1639/14

S/I.D.S.
G. Standy
8-7-01

Examiner:

Commissioner of Patents and Trademarks
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Enclosed is PTO Form 1449 which lists citations which may be material to the patentability of the above-identified application. This Information Disclosure Statement is being submitted prior to any Office Action and no fee is required.

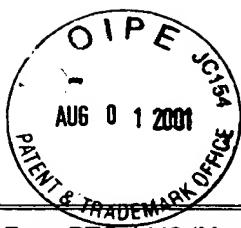
Also enclosed are copies of the references cited. These are being submitted in compliance with the duty of disclosure defined in 37 C.F.R. 1.56. The Examiner is requested to make these citations of official record in this application.

This Information Disclosure Statement Under 37 C.F.R. 1.56 is not to be construed as a representation that a search has been made, that additional matter which is material to the examination of this application does not exist, or that any one or more of these citations constitutes prior art.

Respectfully submitted,


Mark M. Friedman
Attorney for Applicant
Registration No. 33,883

Date: July 29, 2001



Sheet 1 of 1

Form PTO-1449 (Modified)			Atty. Docket No. 1639/14		Application No. 09/762,473			
INFORMATION DISCLOSURE CITATION IN AN APPLICATION (USE SEVERAL SHEETS IF NECESSARY)			Applicant: Du-Nour					
			Filing Date: 7 February 2001		Group Art Unit: 2877			
U.S. PATENT DOCUMENTS								
	EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME		CLASS	SUB-CLASS	FILING DATE
AA								
AB								
AC								
AD								
AE								
AF								
AG								
AH								
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
AI							YES	NO
AJ								
AK								
AL								
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
AM		Prabhaker S. Naidu, <i>Modern Spectrum Analysis of Time Series</i> , CRC Press 1996						
AN								
AO								
AP								
EXAMINER			DATE CONSIDERED					
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformation and not considered. Include copy of this form with next communication to applicant.								